

GENERAL DESCRIPTION

Passivated guaranteed commutation triacs in a plastic envelope intended for use in motor control circuits or with other highly inductive loads. These devices balance the requirements of commutation performance and gate sensitivity. The "sensitive gate" E series and "logic level" D series are intended for interfacing with low power drivers, including micro controllers.

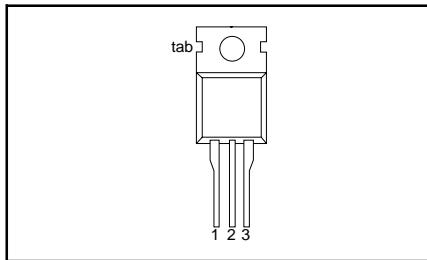
QUICK REFERENCE DATA

SYMBOL	PARAMETER	MAX.	MAX.	UNIT
V_{DRM}	BTA212- BTA212- BTA212-	600D 600E 600F	800E 800F	V
I_{TRMS}	Repetitive peak off-state voltages	600	800	
I_{TSM}	RMS on-state current	12	12	A
	Non-repetitive peak on-state current	95	95	A

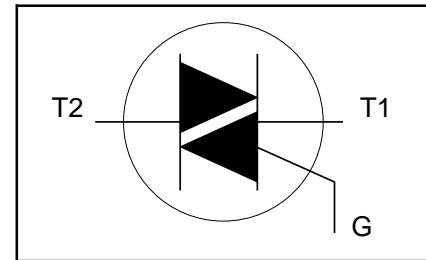
PINNING - TO220AB

PIN	DESCRIPTION
1	main terminal 1
2	main terminal 2
3	gate
tab	main terminal 2

PIN CONFIGURATION



SYMBOL



LIMITING VALUES

Limiting values in accordance with the Absolute Maximum System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V_{DRM}	Repetitive peak off-state voltages		-	-600 600 ¹	V
I_{TRMS}	RMS on-state current	full sine wave; $T_{mb} \leq 99^\circ C$	-	12	A
I_{TSM}	Non-repetitive peak on-state current	full sine wave; $T_j = 25^\circ C$ prior to surge			
I^2t	I^2t for fusing	$t = 20\text{ ms}$	-	95	A
dl_T/dt	Repetitive rate of rise of on-state current after triggering	$t = 16.7\text{ ms}$	-	105	A
I_{GM}	Peak gate current	$t = 10\text{ ms}$	-	45	A ² s
V_{GM}	Peak gate voltage	$I_{TM} = 20\text{ A}; I_G = 0.2\text{ A}; dl_G/dt = 0.2\text{ A}/\mu s$	-	100	A/ μs
P_{GM}	Peak gate power		-	2	W
$P_{G(AV)}$	Average gate power	over any 20 ms period	-	5	W
T_{stg}	Storage temperature		-40	150	°C
T_j	Operating junction temperature		-	125	°C

¹ Although not recommended, off-state voltages up to 800V may be applied without damage, but the triac may switch to the on-state. The rate of rise of current should not exceed 15 A/ μs .

THERMAL RESISTANCES

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$R_{th\ j\text{-}mb}$	Thermal resistance junction to mounting base	full cycle	-	-	1.5	K/W
$R_{th\ j\text{-}a}$	Thermal resistance junction to ambient	half cycle in free air	-	60	2.0	K/W

STATIC CHARACTERISTICS

$T_j = 25^\circ\text{C}$ unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.			UNIT
I_{GT}	Gate trigger current ²	$V_D = 12\text{ V}; I_T = 0.1\text{ A}$ T2+ G+ T2+ G- T2- G-	-	...D	...D	...E	...F	mA
			-	1.0	5	10	25	
			-	2.2	5	10	25	
I_L	Latching current	$V_D = 12\text{ V}; I_{GT} = 0.1\text{ A}$ T2+ G+ T2+ G- T2- G-	-	3.3	5	10	25	mA
			-	6	15	25	30	
			-	6	25	30	40	
I_H	Holding current	$V_D = 12\text{ V}; I_{GT} = 0.1\text{ A}$	-	9	25	30	40	mA
			-	3.8	15	25	30	
			...D, E, F					
V_T V_{GT}	On-state voltage Gate trigger voltage	$I_T = 17\text{ A}$ $V_D = 12\text{ V}; I_T = 0.1\text{ A}$ $V_D = 400\text{ V}; I_T = 0.1\text{ A};$ $T_j = 125^\circ\text{C}$	-	1.3	1.6			V
			-	0.7	1.5			
I_D	Off-state leakage current	$V_D = V_{DRM(\text{max})};$ $T_j = 125^\circ\text{C}$	0.25	0.4	-			V
			-	0.1	0.5			mA

DYNAMIC CHARACTERISTICS

$T_j = 25^\circ\text{C}$ unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS	MIN.			TYP.	MAX.	UNIT
dV_D/dt	Critical rate of rise of off-state voltage	$V_{DM} = 67\% V_{DRM(\text{max})};$ $T_j = 110^\circ\text{C}$; exponential waveform; gate open circuit	BTA212- 20	...D	...E	...F	...D	V/ μs
				60	70	30	-	
				-	-	-	-	
dl_{com}/dt	Critical rate of change of commutating current	$V_{DM} = 400\text{ V}; T_j = 110^\circ\text{C};$ $I_{T(\text{RMS})} = 12\text{ A};$ $dV_{com}/dt = 20\text{ V}/\mu\text{s}$; gate open circuit	1.8	3.5	5	3	-	A/ms
				-	-	-	-	
				-	-	-	-	
dl_{com}/dt	Critical rate of change of commutating current	$V_{DM} = 400\text{ V}; T_j = 110^\circ\text{C};$ $I_{T(\text{RMS})} = 12\text{ A};$ $dV_{com}/dt = 0.1\text{ V}/\mu\text{s}$; gate open circuit	5	16	19	100	-	A/ms
				-	-	-	-	
				-	-	-	-	
t_{gt}	Gate controlled turn-on time	$I_{TM} = 12\text{ A}; V_D = V_{DRM(\text{max})};$ $I_G = 0.1\text{ A}; dl_G/dt = 5\text{ A}/\mu\text{s}$...D, E, F	-	-	-	2	μs
				-	-	-	-	
				-	-	-	-	

² Device does not trigger in the T2-, G+ quadrant.

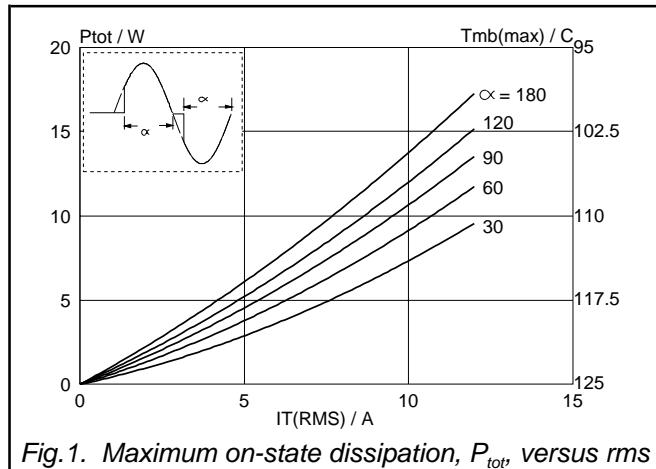


Fig.1. Maximum on-state dissipation, P_{tot} , versus rms on-state current, $I_T(RMS)$, where α = conduction angle.

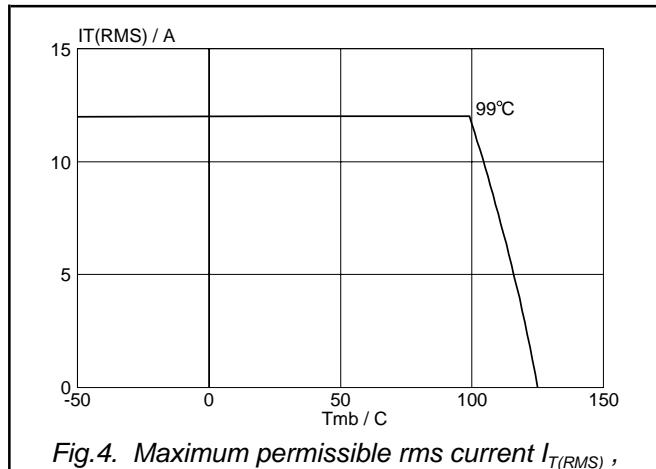


Fig.4. Maximum permissible rms current $I_T(RMS)$, versus mounting base temperature T_{mb} .

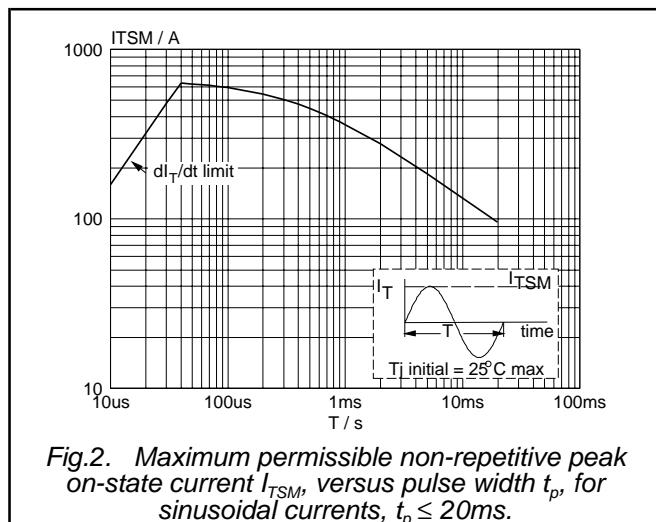


Fig.2. Maximum permissible non-repetitive peak on-state current I_{TSM} , versus pulse width t_p , for sinusoidal currents, $t_p \leq 20\text{ms}$.

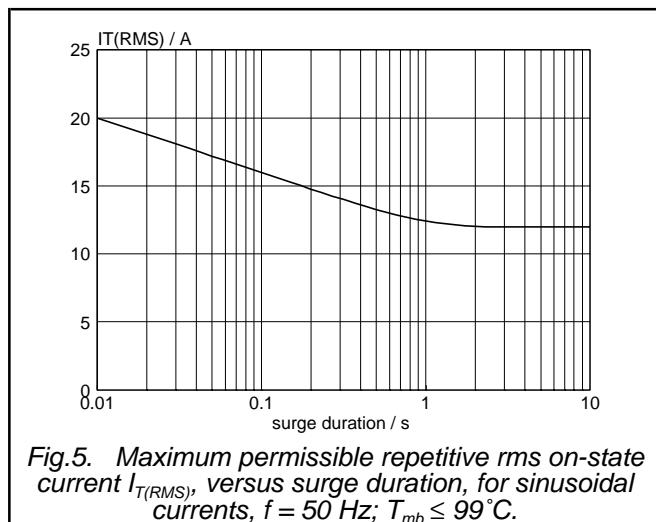


Fig.5. Maximum permissible repetitive rms on-state current $I_{T(RMS)}$, versus surge duration, for sinusoidal currents, $f = 50\text{ Hz}$; $T_{mb} \leq 99^{\circ}\text{C}$.

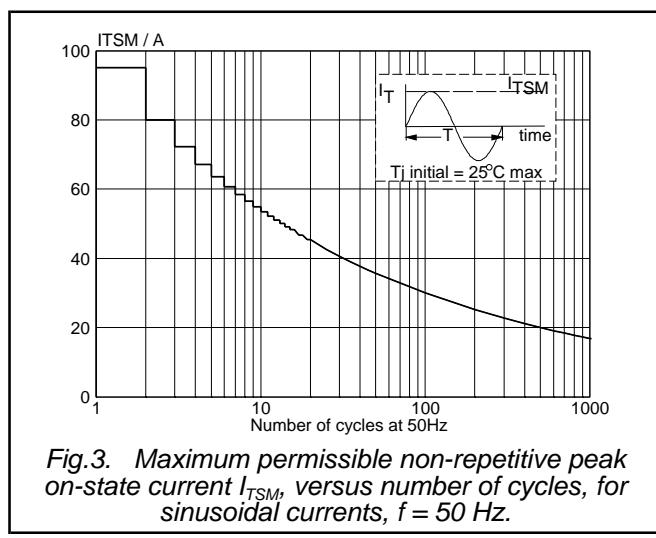


Fig.3. Maximum permissible non-repetitive peak on-state current I_{TSM} , versus number of cycles, for sinusoidal currents, $f = 50\text{ Hz}$.

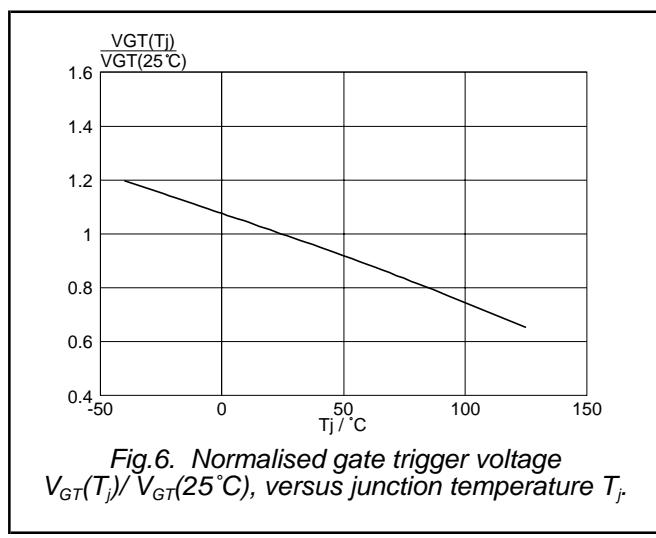


Fig.6. Normalised gate trigger voltage $V_{GT}(T_j)/V_{GT}(25^{\circ}\text{C})$, versus junction temperature T_j .

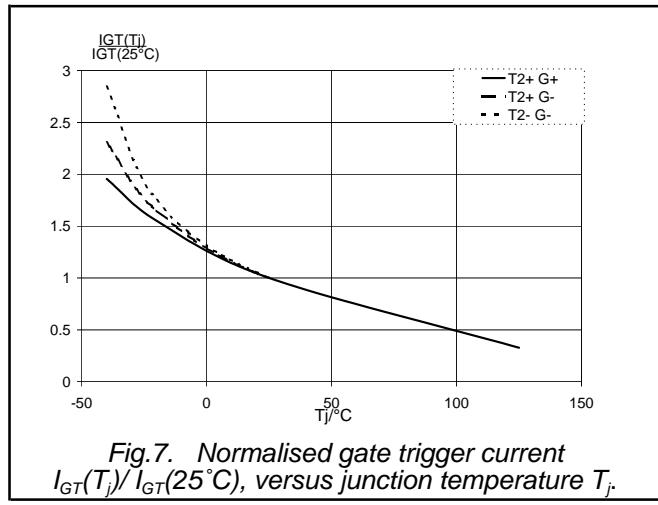


Fig.7. Normalised gate trigger current $I_{GT}(T_j)/I_{GT}(25^\circ\text{C})$, versus junction temperature T_j .

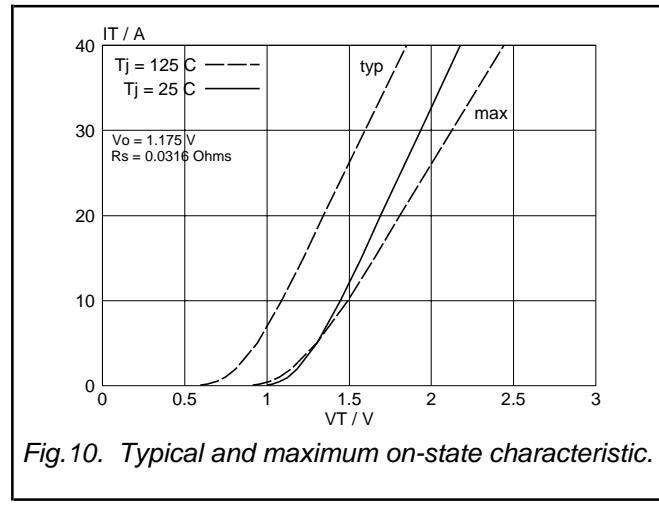


Fig.10. Typical and maximum on-state characteristic.

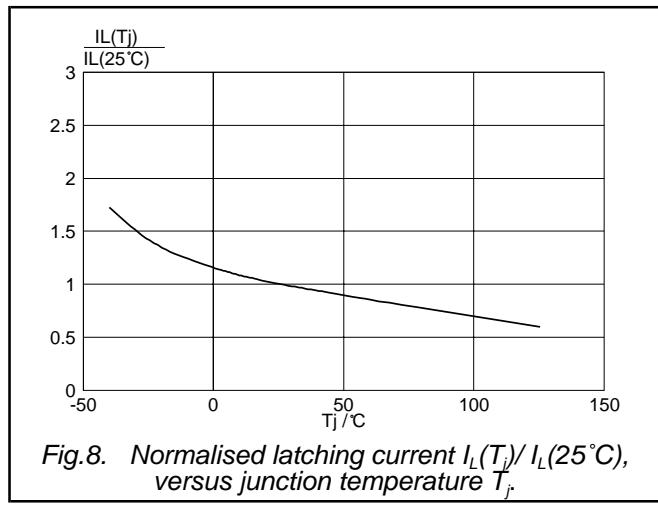


Fig.8. Normalised latching current $I_L(T_j)/I_L(25^\circ\text{C})$, versus junction temperature T_j .

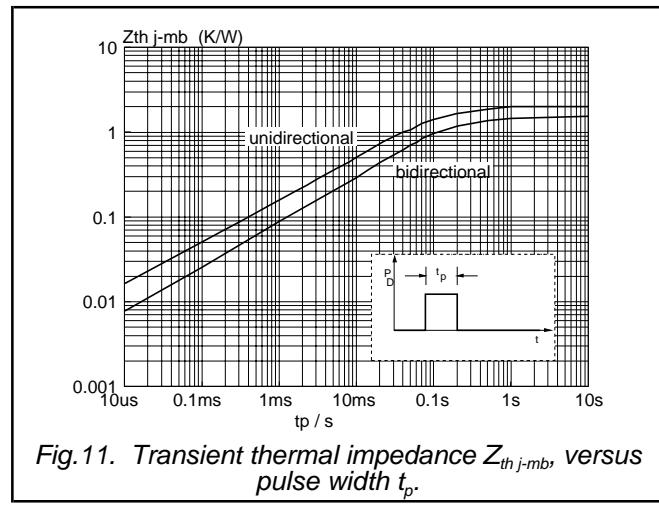


Fig.11. Transient thermal impedance $Z_{th,j-mb}$, versus pulse width t_p .

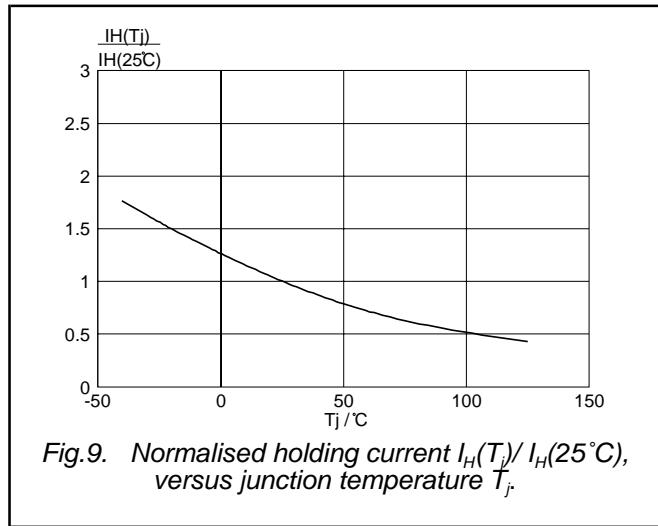


Fig.9. Normalised holding current $I_H(T_j)/I_H(25^\circ\text{C})$, versus junction temperature T_j .

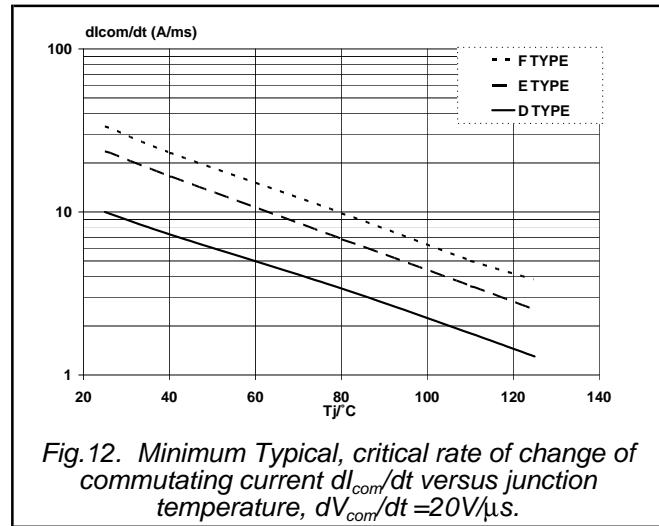


Fig.12. Minimum Typical, critical rate of change of commutating current dI_{com}/dt versus junction temperature, $dV_{com}/dt = 20\text{V}/\mu\text{s}$.

MECHANICAL DATA

Dimensions in mm

Net Mass: 2 g

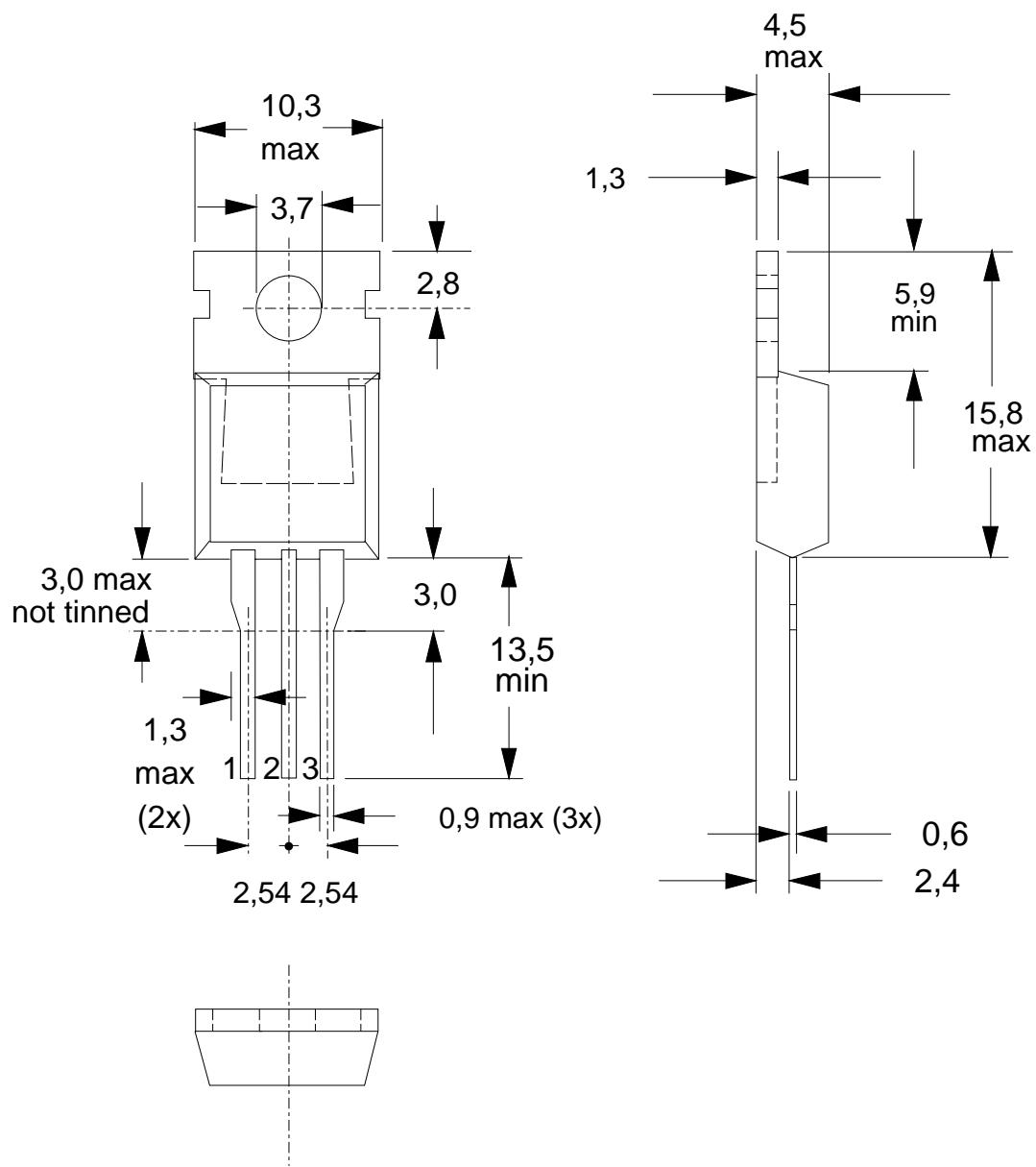


Fig.13. SOT78 (TO220AB). pin 2 connected to mounting base.

Notes

1. Refer to mounting instructions for SOT78 (TO220) envelopes.
2. Epoxy meets UL94 V0 at 1/8".